



2nd JST International Symposium on Dependable VLSI Systems (DVLSI 2013)

December 6-7, 2013

Kikai Shinko Kaikan Building, Tokyo, Japan

Sponsored by JST CREST/DVLSI

Co-Sponsored by Kyushu Institute of Technology

In cooperation with the IEICE Electronics Society Technical Committee on Integrated Circuits and Devices (tentative)

In cooperation with the IEICE Information and Systems Society Technical Committee on Dependable Computing

This is an announcement of the second JST International Symposium of Dependable VLSI Systems to be held in Tokyo on December 6-7, 2013. The purpose of this meeting is to review and discuss the progress and outcome of a research program entitled, "Dependable VLSI Systems (DVLSI)" among professionals having special interest in the dependability of electronic systems. This unique program, sponsored by JST (Japan Science and Technology Agency), was initiated in 2007 for the purpose of developing basic VLSI technologies to enhance the dependability of systems. The program addresses various important issues of dependability ranging from the chip level all the way up to the systems level. Systems addressed include automotive, robotic, plant control, transportation, telecom, data processing to aerospace. The program consists of eleven (11) projects which has dealt with key issues, some arising from small feature sizes and others from design complexity. At the symposium this year, all eleven projects are reviewed including those which completed the term of five years and a half in March 2013. We will solicit guest speakers and panelists from various organizations of excellence where related objectives are being pursued. Invitation is being extended to everybody who has ever attended the past DVLSI meetings or to anybody who has special interest in the systems dependability and its implications in VLSI.

Venue

Kikai Shinko Kaikan Building,
3-5-8 Shibakoen, Minato-ku, Tokyo 105-0011 Japan

Access

1. 6-minute walk from Kamiyacho Sta., Tokyo Metro Hibiya Line
2. 8-minute walk from Onarimon Sta., Toei Mita Line
3. 10-minute walk from Akabanebashi Sta., Toei Oedo Line

<http://www.jspmi.or.jp/kaigishitsu/access.html>



Registration

Invited attendees: Invitation will be extended to solicit attendance.

General registration: welcome to pre-register at <http://www.dvlsi.jst.go.jp/english/index.html>

Registration Fee: free for all sessions, and 6000 JPY for banquet

Contact: symposium secretariat (k2tsujim@jst.go.jp or dvlsi@dvlsi.jst.go.jp)



JST/CREST Program 'Dependable VLSI Systems'

<http://www.dvlsi.jst.go.jp/english/index.html>

Program Committees

Chair:	Seiji Kajihara	(Kyushu Institute of Technology)
Secretary:	Satoshi Otake	(Oita University)
Members:	Masahiko Yoshimoto	(Kobe University)
	Tomohiro Yoneda	(The National Institute of Informatics)
	Hiroshi Kawaguchi	(Kobe University)

Research Supervisor

Shojiro Asai (Vice President, Rigaku Corporation)

Research Area Advisers

Masatoshi Ishikawa	(Professor, The University of Tokyo)
Tohru Kikuno	(Professor, Osaka Gakuin University)
Tadayuki Takahashi	(Professor, Japan Aerospace Exploration Agency)
Naoki Nishi	(General Manager, NEC Corp., System IP Core Research Lab.)
Atsushi Hasegawa	(Director, Renesas Electronics Corp.)
Toshio Masubuchi	(Director, Toshiba Corp. Semiconductor & Storage Company)
Kazuo Yano	(Senior Chief Researcher, Hitachi Ltd. Central Research Lab.)
Koichiro Takayama	(Chief Researcher, Fujitsu Laboratory Ltd.)

Principal Investigators and Research Themes

1. Hidetoshi Onodera (Kyoto University) URL <http://www.tamaru.kuee.kyoto-u.ac.jp/>
“Dependable VLSI platform using robust fabrics”
2. Shuichi Sakai (The University of Tokyo) URL <http://www.mtl.t.u-tokyo.ac.jp/index-e.html>
“Ultra Dependable VLSI by collaboration of formal verifications and architectural technologies”
3. Kazuo Tsubouchi (Tohoku University) URL <http://www.riec.tohoku.ac.jp/lab/it-21-mob/index-e.html>
“Development of Dependable Wireless System and Device”
4. Hiroto Yasuura (Kyushu University) URL <http://soc.ait.kyushu-u.ac.jp/SOC/>
“Modeling, Detection, Correction and Recovery Techniques for Unified Dependable Design”
5. Seiji Kajihara (The Kyushu Institute of Technology) URL <http://aries3a.cse.kyutech.ac.jp/>
“Circuit and system mechanisms for high field reliability”
6. Masahiko Yoshimoto (Kobe University) URL <http://www28.cs.kobe-u.ac.jp/en/>
“Dependable SRAM Techniques for Highly Reliable VLSI System”
7. Tomohiro Yoneda (National Institute of Informatics) URL http://www.nii.ac.jp/staff/Yoneda_Tomohiro.shtml
“Development of Dependable Network-on-Chip Platform”
8. Mitsumasa Koyanagi (Tohoku University) URL <http://www.sd.mech.tohoku.ac.jp/Site/Home.html>
“Three-Dimensional VLSI System with Self-Restoration Function”
9. Ken Takeuchi (Chuo University) URL http://www.takeuchi-lab.org/index_e.htm
“Dependable Wireless Solid-State Drive (SSD)”
10. Takeshi Fujino (Ritsumeikan University) URL <http://www.ritsumeikan.ac.jp/se/re/fujinolab/index-e.html>
“The Design and Evaluation Methodology of Dependable VLSI for Tamper Resistance”
11. Nobuyuki Yamasaki (Keio University) URL <http://www.ny.ics.keio.ac.jp/>
“Fundamental Technology on Dependable SoC and SiP for Embedded Real-Time Systems”